

**IN THE UNITED STATES**  
**PATENT AND TRADEMARK OFFICE**

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SERIAL NO.: Continuation of 09/502,534

PARENT FILING DATE: February 10, 2000

TITLE: Inspecting Optical Masks With Electron Beam Microscopy

EXAMINER: Unknown

GROUP ART UNIT: Unknown

ATTY. DKT. NO.: 22120-08965

**CERTIFICATE OF MAILING**

I hereby certify that this correspondence, including the enclosures identified herein, are being deposited with the United States Postal Service as Express Mail in an envelope addressed to: Mail Stop Patent Application, Commissioner For Patents, P. O. Box 1450, Alexandria, VA 22313-1450, on the date shown below. This correspondence is being deposited with the United States Postal Service "Express Mail Post Office to Addressee" service pursuant to 37 CFR 1.10: Express Mail No. EV 442673984 US.

Dated: March 15, 2004

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MAIL STOP PATENT APPLICATION  
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PRELIMINARY AMENDMENT

Sir:

This application is a continuation of pending application number 09/502,534, filed on February 10, 2000, which was a reissue application for patent no. 5,717,204 issued February 10, 1998, which is a continuation of 08/252,763, which is a CIP of 07/889,460, and is in response to the Notice of Appeal filed August 14, 2003, which established a non-statutory period for filing an

appellate brief that expired on March 14, 2004 (a Sunday). A fee for a five-month extension of time is included herewith.